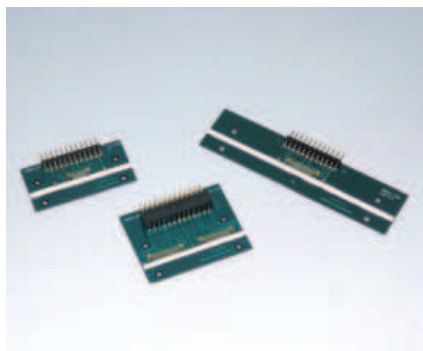


Photodiode arrays with amplifier



S8865-64G/-128G/-256G
S8866-64G-02/-128G-02

Photodiode array combined with signal processing IC for X-ray detection

The S8866-64G-02/-128G-02 are photodiode arrays with an amplifier and a phosphor sheet attached to the photosensitive area for X-ray detection. The signal processing circuit chip is formed by CMOS process and incorporates a timing generator, shift register, charge amplifier array, clamp circuit and hold circuit, making the external circuit configuration simple. A long, narrow image sensor can be configured by arranging multiple arrays in a row. As the dedicated driver circuit, the C9118 series (sold separately) is provided. (Not compatible with the S8865-256G and S8866-64G-02.)

Features

- **Large element pitch: 5 types available**
S8865-64G: 0.8 mm pitch × 64 ch
S8865-128G: 0.4 mm pitch × 128 ch
S8865-256G: 0.2 mm pitch × 256 ch
S8866-64G-02: 1.6 mm pitch × 64 ch
S8866-128G-02: 0.8 mm pitch × 128 ch
- **5 V power supply operation**
- **Simultaneous integration by using a charge amplifier array**
- **Sequential readout with a shift register**
(Data rate: 500 kHz max.)
- **Low dark current due to zero-bias photodiode operation**
- **Integrated clamp circuit allows low noise and wide dynamic range**
- **Integrated timing generator allows operation at two different pulse timings**
- **Detectable energy range: 30 k to 100 keV**

Applications

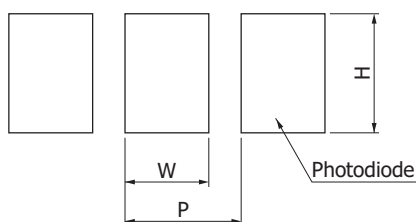
- **Line sensors for X-ray detection**

Structure

Parameter	Symbol*1	S8865-64G	S8865-128G	S8865-256G	S8866-64G-02	S8866-128G-02	Unit
Element pitch	P	0.8	0.4	0.2	1.6	0.8	mm
Element diffusion width	W	0.7	0.3	0.1	1.5	0.7	mm
Element height	H	0.8	0.6	0.3	1.6	0.8	mm
Number of elements	-	64	128	256	64	128	-
Effective photosensitive area length	-	51.2	51.2	51.2	102.4	102.4	mm
Board material	-	Glass epoxy					-

*1: Refer to following figure.

Enlarged drawing of photosensitive area



KMPDC0072EA

Absolute maximum ratings

Parameter	Symbol	Value	Unit
Supply voltage	Vdd	-0.3 to +6	V
Reference voltage	Vref	-0.3 to +6	V
Photodiode voltage	Vpd	-0.3 to +6	V
Gain selection terminal voltage	Vgain	-0.3 to +6	V
Master/slave selection voltage	Vms	-0.3 to +6	V
Clock pulse voltage	V (CLK)	-0.3 to +6	V
Reset pulse voltage	V (RESET)	-0.3 to +6	V
External start pulse voltage	V (EXTSP)	-0.3 to +6	V
Operating temperature*2	Topr	-5 to +60	°C
Storage temperature*2	Tstg	-10 to +70	°C

*2: No condensation

Recommended terminal voltage

Parameter	Symbol	Min.	Typ.	Max.	Unit
Supply voltage	Vdd	4.75	5	5.25	V
Reference voltage	Vref	4	4.5	4.6	V
Photodiode voltage	Vpd	-	Vref	-	V
Gain selection terminal voltage	High gain	Vdd - 0.25	Vdd	Vdd + 0.25	V
	Low gain	0	-	0.4	V
Master/slave selection voltage	High level*3	Vdd - 0.25	Vdd	Vdd + 0.25	V
	Low level*4	0	-	0.4	V
Clock pulse voltage	High level	3.3	Vdd	Vdd + 0.25	V
	Low level	0	-	0.4	V
Reset pulse voltage	High level	3.3	Vdd	Vdd + 0.25	V
	Low level	0	-	0.4	V
External start pulse voltage	High level	Vdd - 0.25	Vdd	Vdd + 0.25	V
	Low level	0	-	0.4	V

*3: Parallel

*4: Serial at 2nd or later stages

Electrical characteristics [Ta=25 °C, Vdd=5 V, V(CLK)=V(RESET)=5 V]

Parameter	Symbol	Min.	Typ.	Max.	Unit
Clock pulse frequency*5	f(CLK)	40	-	2000	kHz
Line rate	S8865-64G	-	7339	-	Lines/s
	S8865-128G, S8866-128-02G	-	3784	-	
	S8865-256G	-	1922	-	
	S8866-64G-02	-	6838	-	
Output impedance	Zo	-	3	-	kΩ
Power consumption	S8865-64G, S8866-64G-02	-	100	-	mW
	S8865-128G, S8866-128G-02	-	180	-	
	S8865-256G	-	360	-	
Charge amp feedback capacitance	High gain	-	0.5	-	pF
	Low gain	-	1	-	

* 5: Video data rate is 1/4 of clock pulse frequency f(CLK).

Electrical and optical characteristics [Ta=25 °C, Vdd=5 V, V(CLK)=V(RESET)=5 V, Vgain=5 V (High gain), 0 V (Low gain)]

S8865-64G/-128G/-256G

Parameter		Symbol	S8865-64G			S8865-128G			S8865-256G			Unit
			Min.	Typ.	Max.	Min.	Typ.	Max.	Min.	Typ.	Max.	
Peak sensitivity wavelength*6		λp	-	720	-	-	720	-	-	720	-	nm
Dark output voltage*7	High gain	Vd	-	0.01	0.2	-	0.01	0.2	-	0.01	0.2	mV
	Low gain		-	0.005	0.1	-	0.005	0.1	-	0.005	0.1	
Saturation output voltage		Vsat	3.0	3.5	-	3.0	3.5	-	3.0	3.5	-	V
Saturation exposure*6 *8	High gain	Esat	-	0.8	1.0	-	2.4	3.0	-	15	19	m lx · s
	Low gain		-	1.6	2.0	-	4.8	6.0	-	30	37.5	
Photo sensitivity*6 *8	High gain	S	3520	4400	-	1200	1500	-	200	250	-	V/lx · s
	Low gain		1760	2200	-	600	750	-	100	125	-	
Photo response non-uniformity*9	3 channels from both ends	PRNU	-	-	-35, +10	-	-	-55, +10	-	-	-70, +10	%
	All channels excluding 3 channels from both ends		-	-	±10	-	-	±10	-	-	±10	
Noise*10	High gain	N	-	1.3	2.0	-	1.0	1.5	-	0.8	1.2	mV rms
	Low gain		-	0.7	1.1	-	0.6	0.9	-	0.5	0.75	
Output offset voltage*11		Vos	-	Vref	-	-	Vref	-	-	Vref	-	V

S8866-64G-02/-128G-02

Parameter		Symbol	S8866-64G-02			S8866-128G-02			Unit
			Min.	Typ.	Max.	Min.	Typ.	Max.	
Peak sensitivity wavelength*6		λp	-	720	-	-	720	-	nm
Dark output voltage*7	High gain	Vd	-	0.01	0.2	-	0.01	0.2	mV
	Low gain		-	0.005	0.1	-	0.005	0.1	
Saturation output voltage		Vsat	3	3.5	-	3	3.5	-	V
Saturation exposure*6 *8	High gain	Esat	-	0.2	0.25	-	0.8	1.0	m lx · s
	Low gain		-	0.4	0.5	-	1.6	2.0	
Photo sensitivity*6 *8	High gain	S	14400	18000	-	3520	4400	-	V/ lx · s
	Low gain		7200	9000	-	1760	2200	-	
Photo response non-uniformity*9	3 channels from both ends	PRNU	-	-	-25, +10	-	-	-35, +10	%
	All channels excluding 3 channels from both ends		-	-	±10	-	-	±10	
Noise*10	High gain	N	-	2.0	3.0	-	1.3	2.0	mVrms
	Low gain		-	1.1	1.7	-	0.7	1.1	
Output offset voltage*11		Vos	-	Vref	-	-	Vref	-	V

*6: Measured without phosphor sheet

 *7: Integration time $t_s=1$ ms

*8: Measured with a 2856 K tungsten lamp

*9: When the photodiode array is exposed to uniform light which is 50% of the saturation exposure, the photo response non-uniformity (PRNU) is defined as follows:

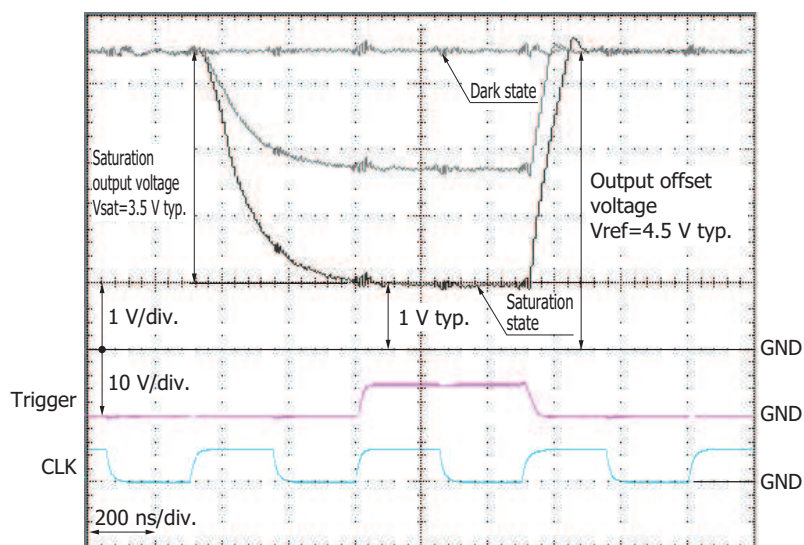
$$PRNU = \Delta X / X \times 100 [\%]$$

 X: average output of all elements, ΔX : difference between X and the maximum or minimum output, whichever is larger.

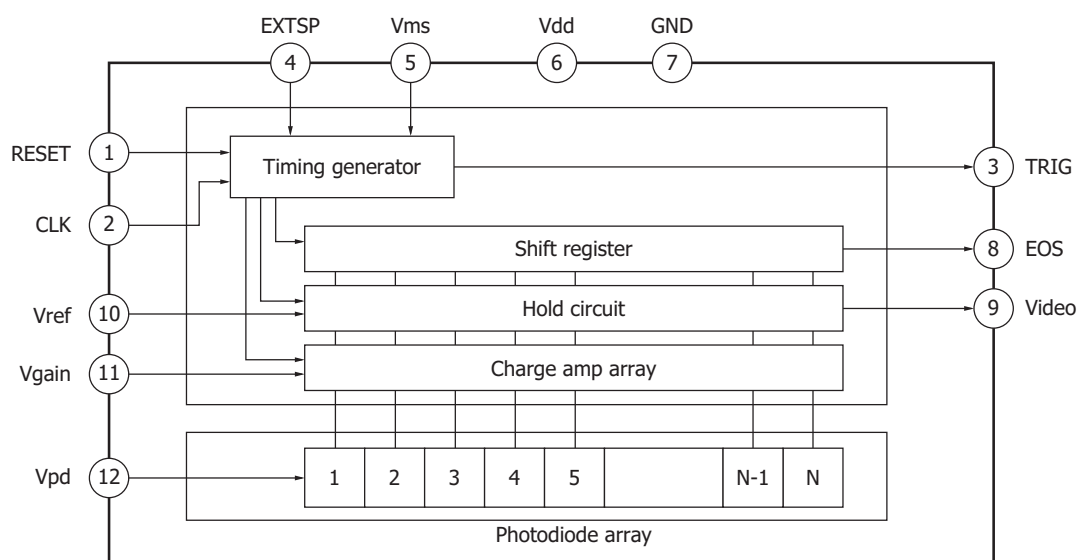
 *10: Measured with a video data rate of 50 kHz and $t_s=1$ ms in dark state

*11: Video output is negative-going output with respect to the output offset voltage.

Output waveform of one element

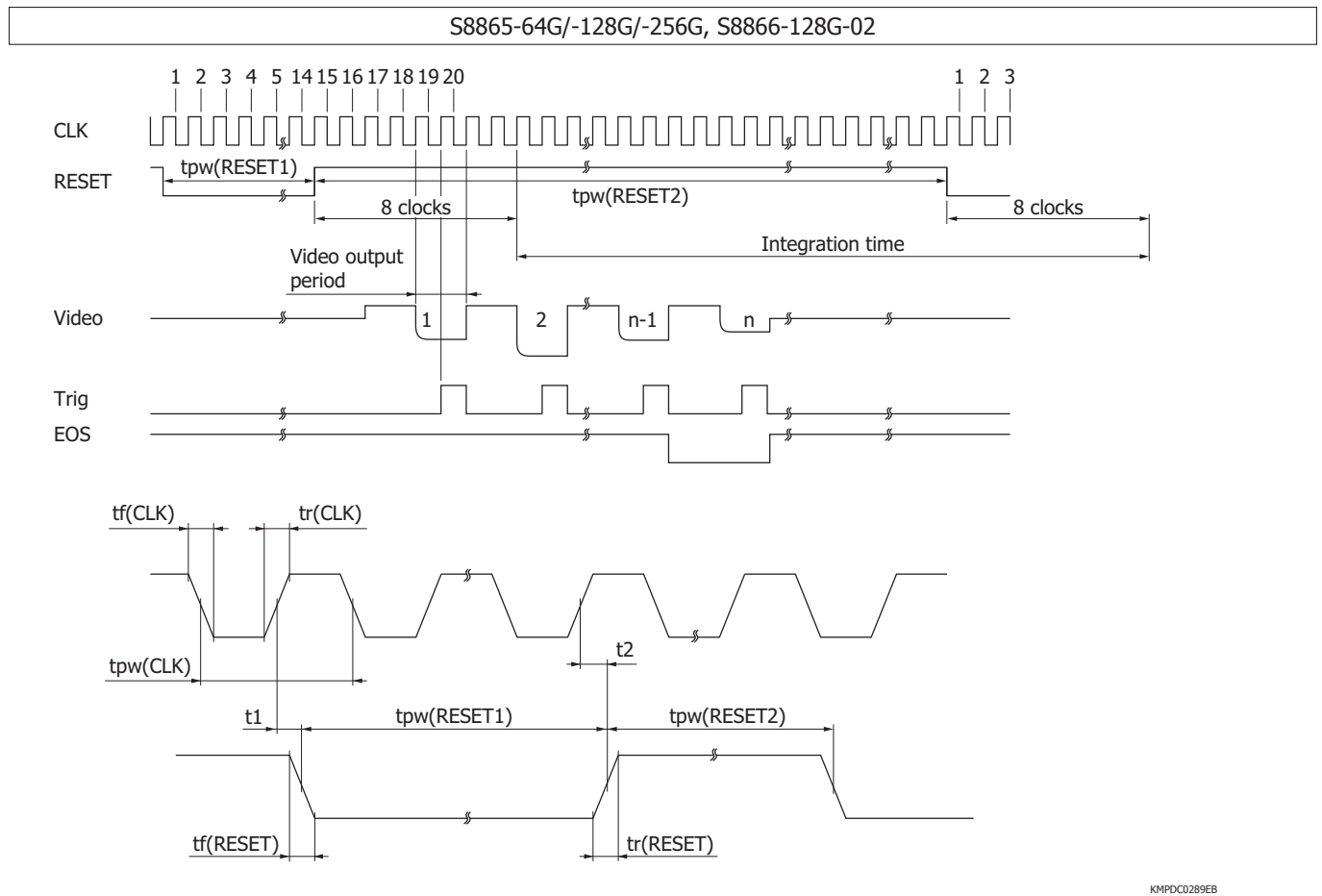


Block diagram



KMPDC0153EA

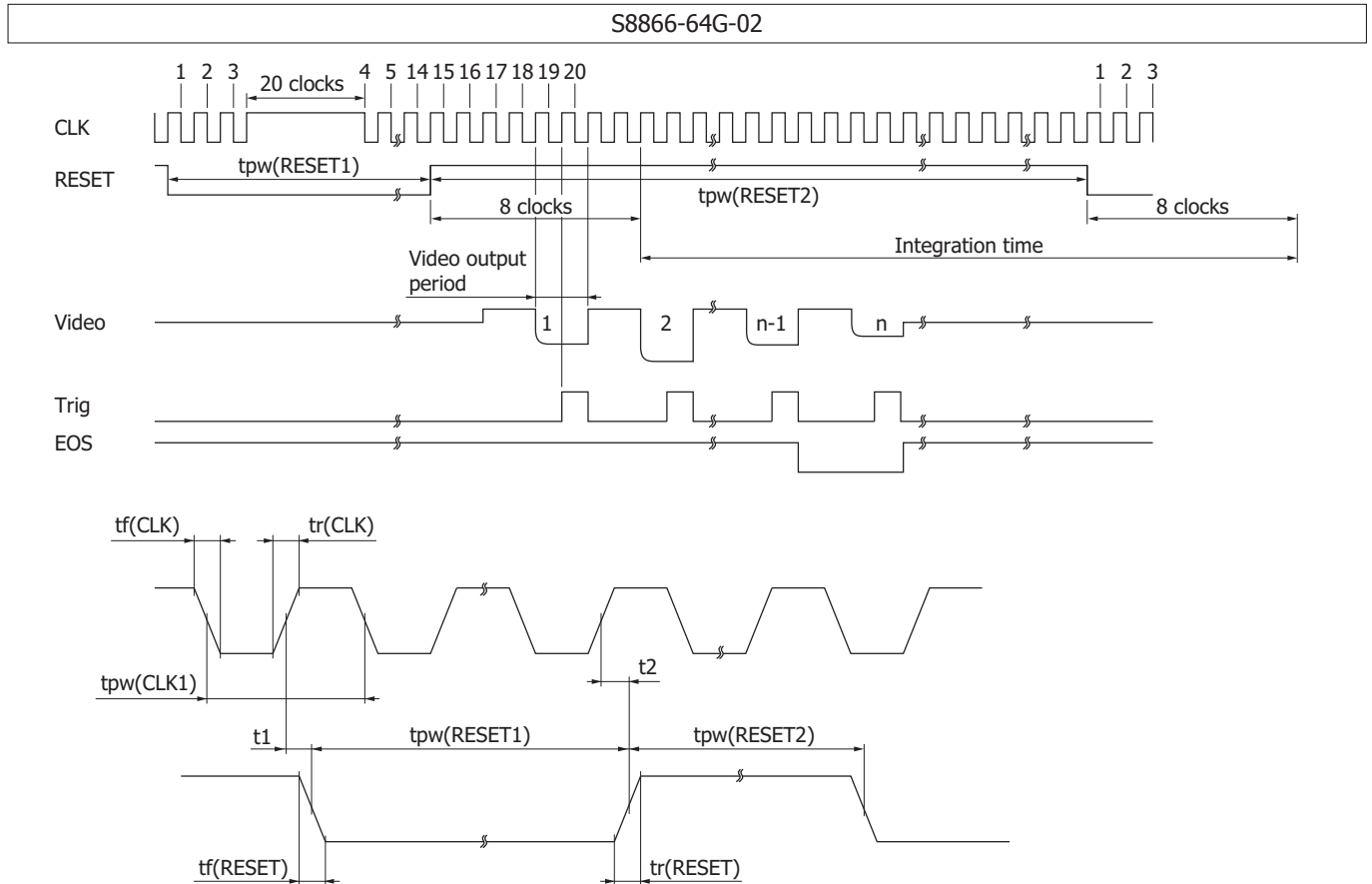
Timing chart



Parameter	Symbol	Min.	Typ.	Max.	Unit
Clock pulse width	tpw(CLK)	500	-	25000	ns
Clock pulse rise/fall times	tr(CLK), tf(CLK)	0	20	30	ns
Reset pulse width 1	tpw(RESET1)	21	-	-	CLK
Reset pulse width 2	tpw(RESET2)	20	-	-	CLK
Reset pulse rise/fall times	tr(RESET), tf(RESET)	0	20	30	ns
Clock pulse-reset pulse timing 1	t1	-20	0	20	ns
Clock pulse-reset pulse timing 2	t2	-20	0	20	ns

1. The internal timing circuit starts operation at the falling edge of CLK immediately after a RESET pulse goes Low.
2. When the falling edge of each CLK is counted as "1 clock", the video signal of the 1st channel appears between "18.5 clocks and 20.5 clocks". Subsequent video signals appear every 4 clocks.
3. The trigger pulse for the 1st channel rises at a timing of 19.5 clocks and then rises every 4 clocks. The rising edge of each trigger pulse is the recommended timing for data acquisition.
4. Signal charge integration time equals the High period of a RESET pulse. However, the charge integration does not start at the rise of a RESET pulse but starts at the 8th clock after the rise of the RESET pulse and ends at the 8th clock after the fall of the RESET pulse.

After the RESET pulse next changes from High to Low, signals integrated within this period are sequentially read out as time-series signals by the shift register operation. The rise and fall of a RESET pulse must be synchronized with the rise of a CLK pulse, but the rise of a RESET pulse must be set outside the video output period. One cycle of RESET pulses cannot be set shorter than the time equal to "16.5 + 4 × N (number of elements)" clocks.
5. The video signal after an EOS signal output becomes a high impedance state, and the video output will be indefinite.

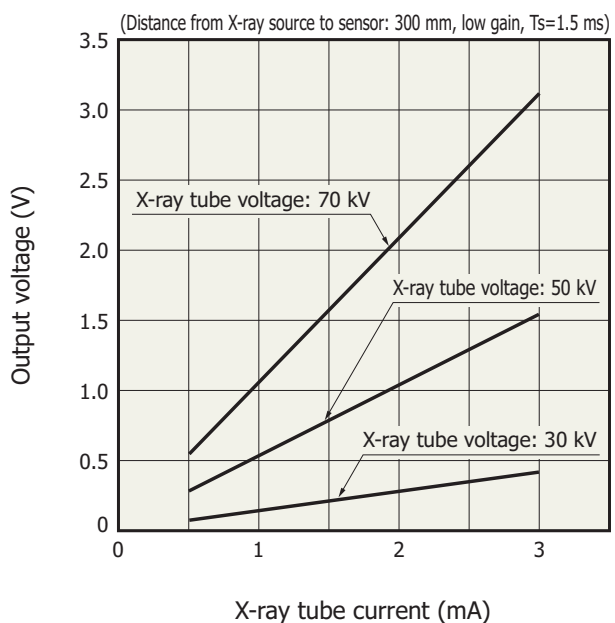


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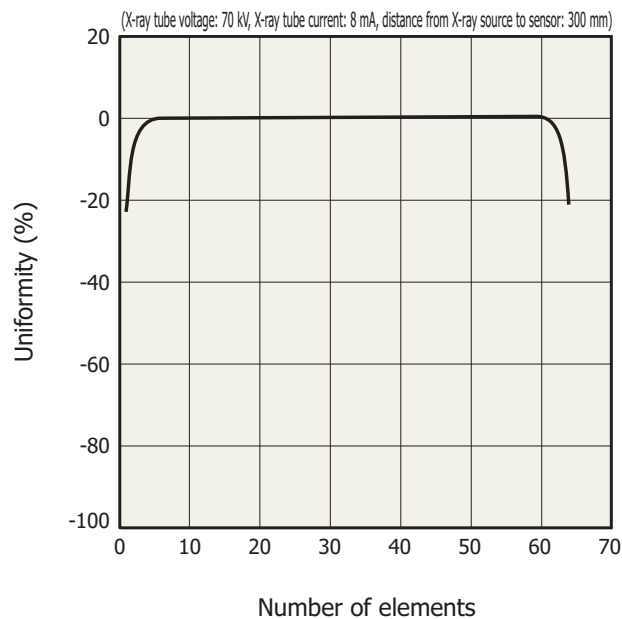
Parameter	Symbol	Min.	Typ.	Max.	Unit
Clock pulse width	tpw (CLK1), tpw (CLK2)	500	-	12500	ns
Clock pulse rise/fall times	tr (CLK), tf (CLK)	0	20	30	ns
Reset pulse width 1	tpw (RESET1)	21	-	-	CLK
Reset pulse width 2	tpw (RESET2)	20	-	-	CLK
Reset pulse rise/fall times	tr (RESET), tf (RESET)	0	20	30	ns
Clock pulse-reset pulse timing 1	t1	-20	0	20	ns
Clock pulse-reset pulse timing 2	t2	-20	0	20	ns

1. The internal timing circuit starts operation at the falling edge of CLK immediately after a RESET pulse goes Low.
2. When the falling edge of each CLK is counted as "1 clock", the video signal of the 1st channel appears between "18.5 clocks and 20.5 clocks". Subsequent video signals appear every 4 clocks.
3. To obtain video signals, extend the High period 3 clocks from the falling edge of CLK immediately after the RESET pulse goes Low, to a 20 clock period.
4. The trigger pulse for the 1st channel rises at a timing of 19.5 clocks and then rises every 4 clocks. The rising edge of each trigger pulse is the recommended timing for data acquisition.
5. Signal charge integration time equals the High period of a RESET pulse. However, the charge integration does not start at the rise of a RESET pulse but starts at the 8th clock after the rise of the RESET pulse and ends at the 8th clock after the fall of the RESET pulse. After the RESET pulse next changes from High to Low, signals integrated within this period are sequentially read out as time-series signals by the shift register operation. The rise and fall of a RESET pulse must be synchronized with the rise of a CLK pulse, but the rise of a RESET pulse must be set outside the video output period. One cycle of RESET pulses cannot be set shorter than the time equal to $36.5 + 4 \times N$ (number of elements) clocks.
6. The video signal after an EOS signal output becomes a high impedance state, and the video output will be indefinite.

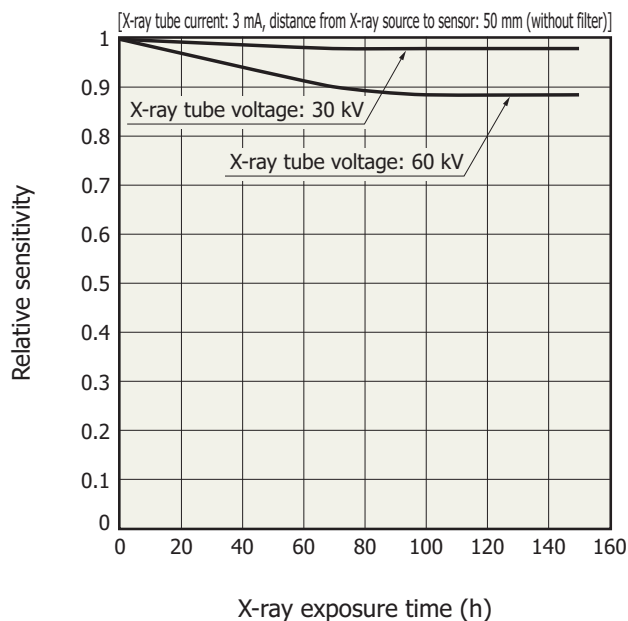
X-ray output example (S8865-64G)



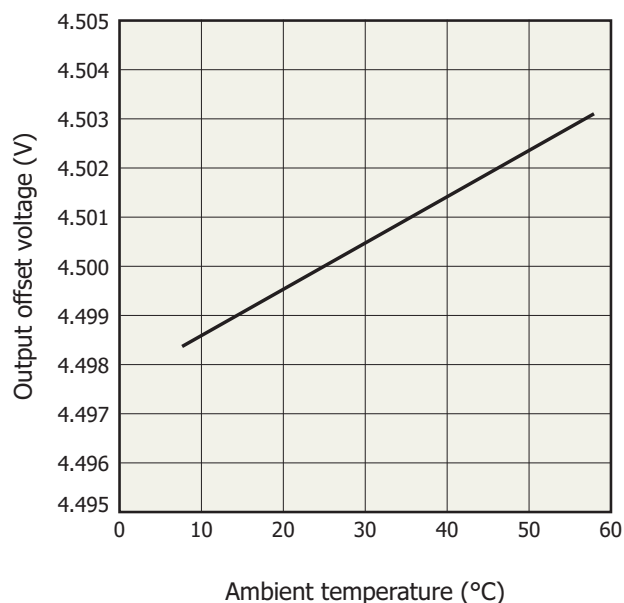
Uniformity example of X-ray output (S8865-64G)



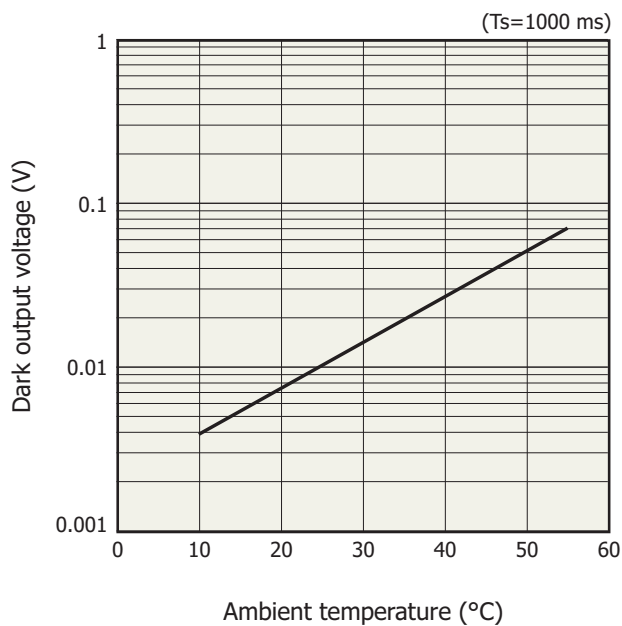
X-ray exposure test example (S8865-128G)



Output offset voltage vs. ambient temperature (measurement example)



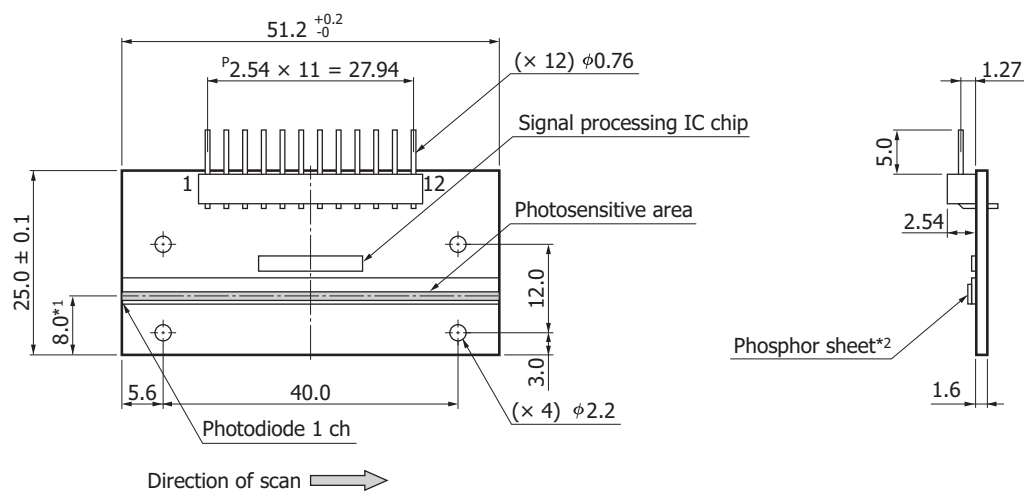
Dark output voltage vs. ambient temperature (measurement example)



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Dimensional outlines (unit: mm)

S8865-64G/-128G

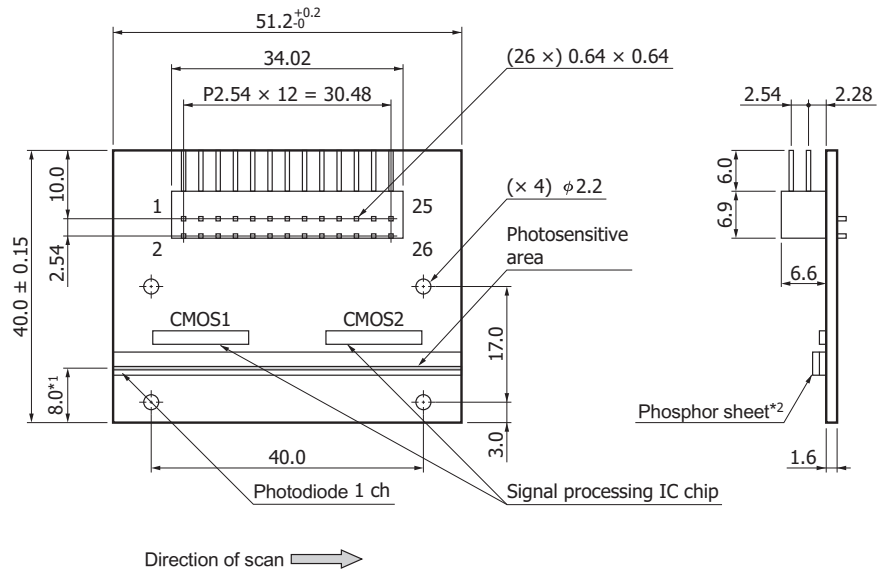


*1: Length from the bottom of the board to the center of photosensitive area
Board: G10 glass epoxy
Connector: PRECI-DIP DURTAL 800-10-012-20-001101

*2: Photodiode array with phosphor sheet: S8865-64G/-128G only
· Material: $Gd_2O_2S:Tb$
· Phosphor thickness: 300 μm Typ.
· Detectable energy range: 30 k to 100 keV

KMPDA0233EC

S8865-256G

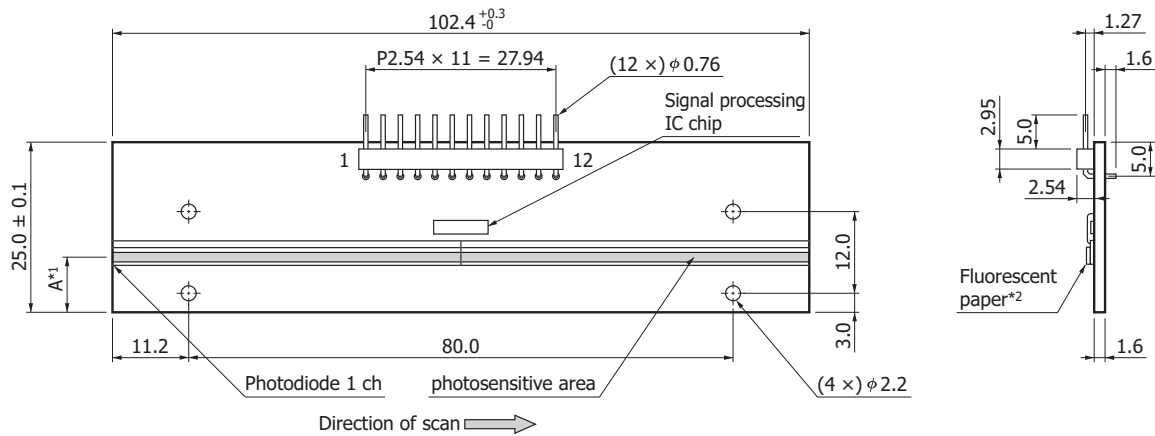


*1: Length from the bottom of the board to the center of photosensitive area
 Board: G10 glass epoxy
 Connector: JAE (Japan Aviation Electronics Industry, Limited)
 PS-26PE-D4LT1-PN1

*2: Photodiode array with phosphor sheet S8865-256G only
 · Material: Gd₂O₂S:Tb
 · Phosphor thickness: 300 μm typ.
 · Detectable energy range: 30 k to 100 keV

KMPDA0234EB

S8866-64G-02/-128G-02



Type no.	A
S8866-64G2	8.2
S8866-128G2	8.0

*1: Length from the bottom of the board to the center of photosensitive area
 Board: G10 glass epoxy
 Connector: PRECI-DIP DURTAL 800-10-012-20-001101

*2: Photodiode array with phosphor sheet
 · Material: Gd₂O₂S:Tb
 · Phosphor thickness: 300 μm typ.
 · Detectable energy range: 30 k to 100 keV

KMPDA0226EC

Pin connection

S8865-64G/-128G, S8866-64G-02/-128G-02

Pin No.	Symbol	Name	Note
1	RESET	Reset pulse	Pulse input
2	CLK	Clock pulse	Pulse input
3	Trig	Trigger pulse	Positive-going pulse output
4	EXTSP	External start pulse	Pulse input
5	Vms	Master/slave selection supply voltage	Voltage input
6	Vdd	Supply voltage	Voltage input
7	GND	Ground	
8	EOS	End of scan	Negative-going pulse output
9	Video	Video output	Negative-going output with respect to Vref
10	Vref	Reference voltage	Voltage input
11	Vgain	Gain selection terminal voltage	Voltage input
12	Vpd	Photodiode voltage	Voltage input

S8865-256G

Pin No.	CMOS1	Pin No.	CMOS2	Name	Note
1	Vpd	14	Vpd	Photodiode voltage	Voltage input
2	RESET	15	RESET	Reset pulse	Pulse input
3	CLK	16	CLK	Clock pulse	Pulse input
4	Trig	17	Trig	Trigger pulse	Positive-going pulse output
5	EXTSP	18	EXTSP	External start pulse	Pulse input
6	Vms	19	Vms	Master/slave selection supply voltage	Voltage input
7	Vdd	20	Vdd	Supply voltage	Voltage input
8	GND	21	GND	Ground	
9	EOS	22	EOS	End of scan	Negative-going pulse output
10	Video	23	Video	Video output	Negative-going output with respect to Vref
11	Vref	24	Vref	Reference voltage	Voltage input
12	Vg	25	Vg	Gain selection terminal voltage	Voltage input
13	Vpd	26	Vpd	Photodiode voltage	Voltage input

Vdd: High gain ($C_f=0.5$ pF) GND: Low gain ($C_f=1$ pF)

S8866-64G/-128G, S8866-64G-02/-128G-02

To serially read out signals from two or more sensors linearly connected, set the 1st sensor to A and the 2nd or later sensors to B. The CLK and RESET pulses should be shared with each sensor and the video output terminal of each sensor connected together.

Setting	Readout method	Vms	EXTSP
A	All stages of parallel readout, serial readout at 1st sensor	Vdd	Vdd
B	Serial readout at 2nd and later sensors	GND	Preceding sensor EOS should be input

KMPDC0288EB

S8865-256G

Signals of channels 1 through 128 are output from CMOS1, while signals of channels 129 through 256 are output from CMOS2. The following two readout methods are available.

(1) Serial readout method

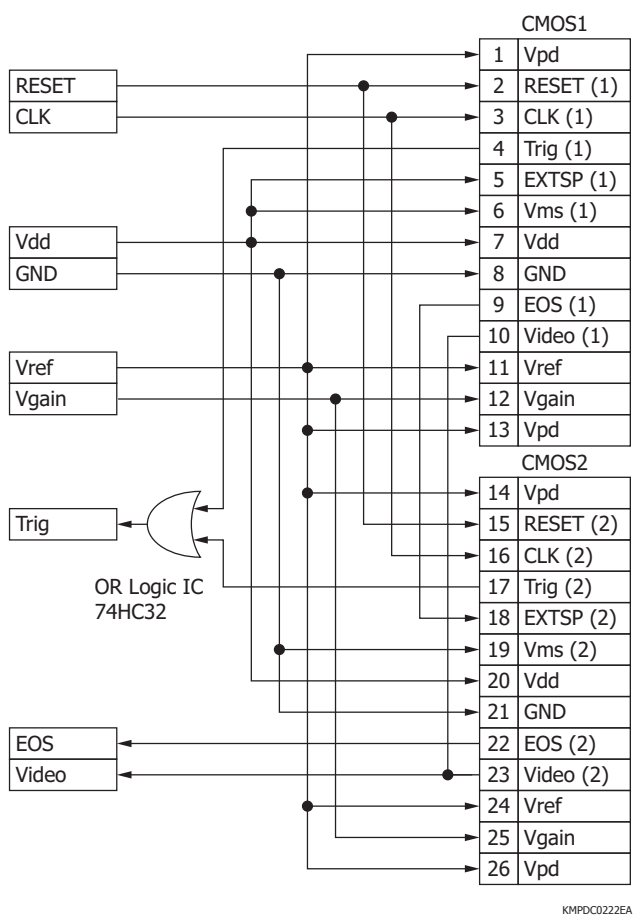
CMOS1 and CMOS2 are connected in serial and the signals of channels 1 through 256 are sequentially read out from one output line. Set CMOS1 as in "A" in the table below, and set CMOS2 as in "B". CMOS1 and CMOS2 should be connected to the same CLK and RESET lines, and their video output terminals to one line.

(2) Parallel readout method

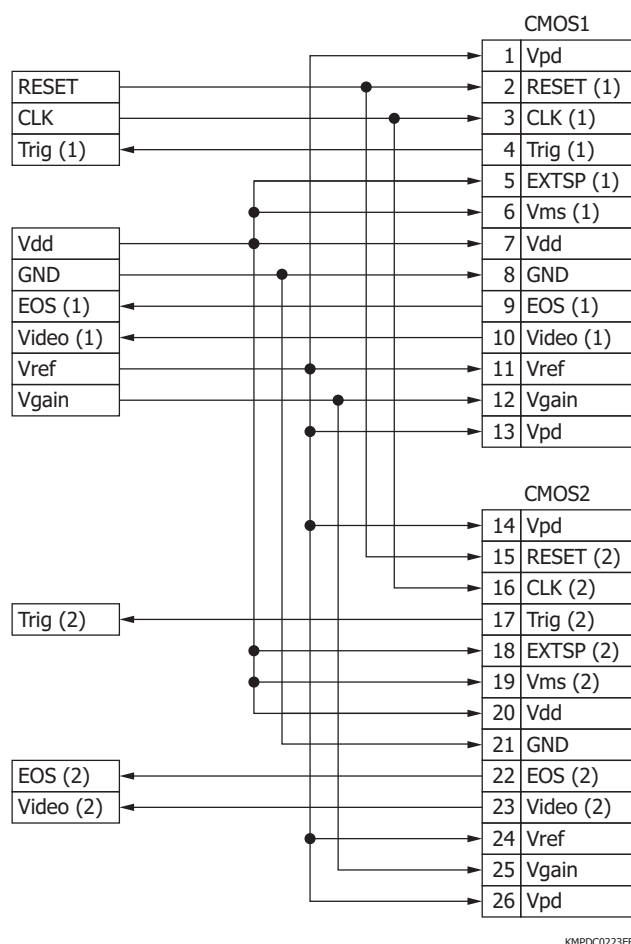
128 channel signals are output in parallel respectively from the output lines of CMOS1 and CMOS2. Set both CMOS1 and CMOS2 as in "A" in the table below.

[Figure 2] Connection

Serial readout method



Parallel readout method



Setting	Vms	EXTSP
A	Vdd	Vdd
B	GND	Preceding sensor EOS should be input

Readout circuit

Check that pulse signals meet the required pulse conditions before supplying them to the input terminals. Video output should be amplified by an operational amplifier that is connected close to the sensor.

Procautions for use

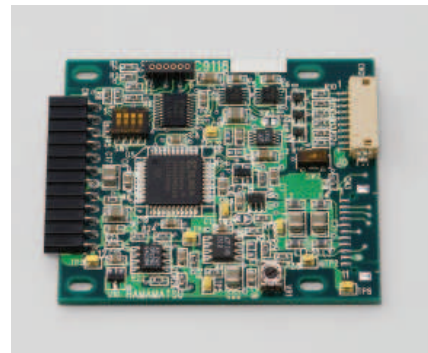
- (1) The signal processing IC chip is protected against static electricity. However, in order to prevent possible damage to the IC chip, take electrostatic countermeasures such as grounding yourself, as well as workbench and tools. Also protect the IC chip from surge voltages from peripheral equipment.
- (2) Gold wires for wire bonding are very thin, so they easily break if subjected to mechanical stress. The signal processing IC chip, wire bonding section and photodiode array chip are covered with resin for protection. However, never touch these portions. Excessive force, if applied, may break the wires or cause malfunction.
Blow air to remove dust or debris if it gets on the protective resin. Never wash them with solvent.
Signals may not be obtained if dust or debris is left or a scratch is made on the protective resin, or the signal processing IC chip or photodiode array chip is nicked.
- (3) The photodiode array characteristics may deteriorate when operated at high humidity, so put it in a hermetically sealed enclosure or case.
When installing the photodiode array on a board, be careful not to cause the board to warp.
- (4) The characteristics of the signal processing IC chip deteriorate if exposed to X-rays. So use a lead shield which is at least 1 mm larger all around than the signal processing IC chip. The 1 mm margin may not be sufficient depending on the incident angle of X-rays. Provide an even larger shield as long as it does not cover the photodiode active area. Since the optimal shield thickness depends on the operating conditions, calculate it by taking the attenuation coefficient of lead into account.
- (5) The sensitivity of the photodiode array chip decreases if continuously exposed to X-rays. The extent of this sensitivity decrease differs depending on the X-ray irradiation conditions, so before beginning measurement, check how much the sensitivity decreases under the X-ray irradiation conditions to be used.

Driver circuit C9118 series (sold separately)

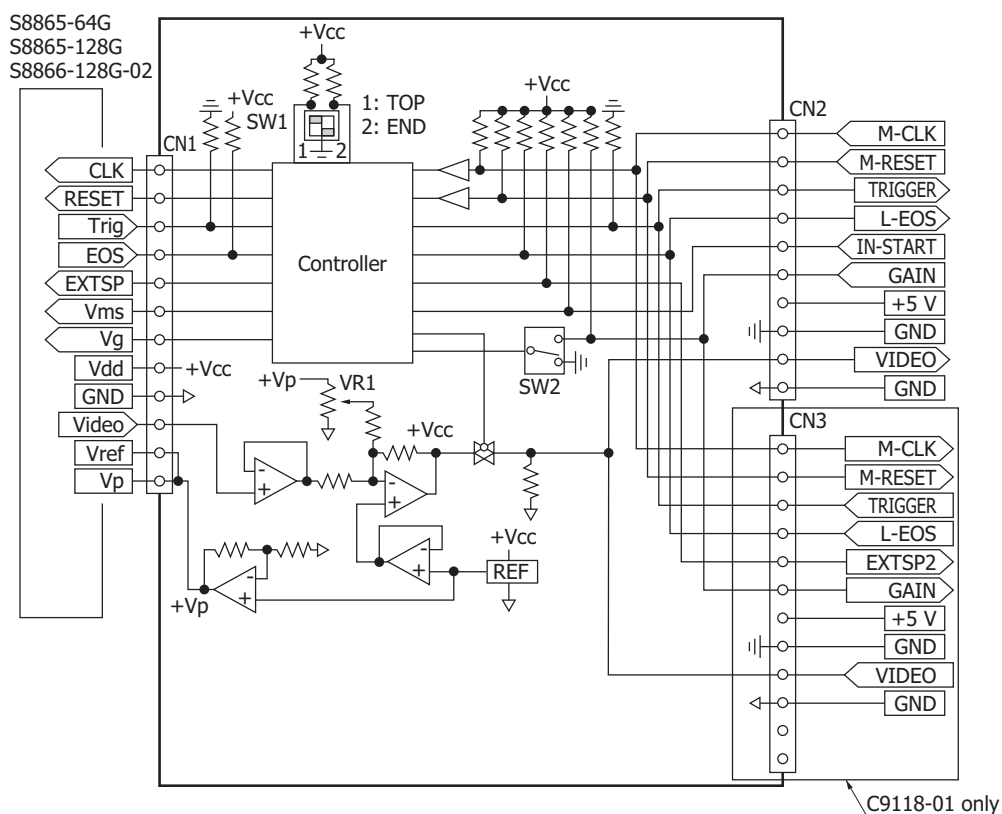
The CMOS driver circuit is designed for the S8865-64G/-128G and S8866-128G-02 photodiode arrays with amplifier. The C9118 series operates a photodiode by just inputting two signals (M-CLK and M-RESET) and a signal +5 V supply. The C9118 is intended for single use or parallel connections, while the C9118-01 is suitable for cascade connections.

Features

- **Single power supply (+5 V) operation**
- **Operation with two input signals (M-CLK and M-RESET)**
- **Compact: 46 × 56 × 5.2[†] mm**



Block diagram

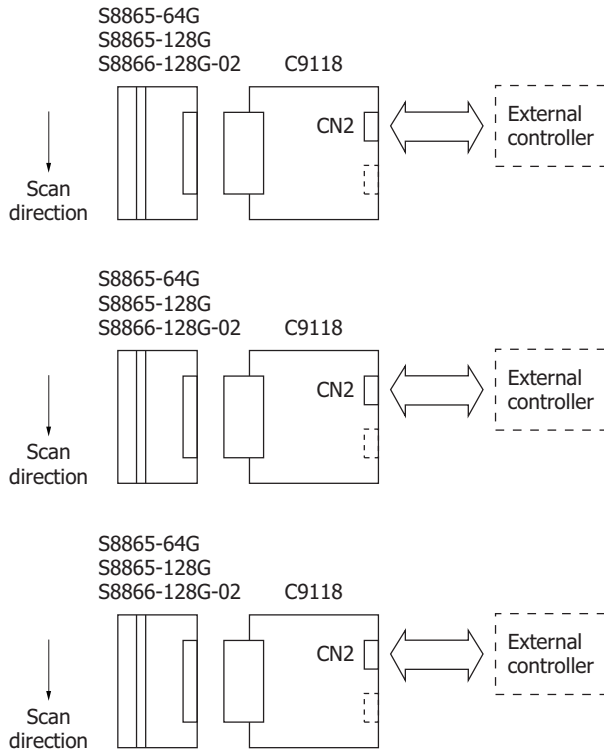


KACCC0455EC

Connection examples

Single or parallel readout example (C9118)

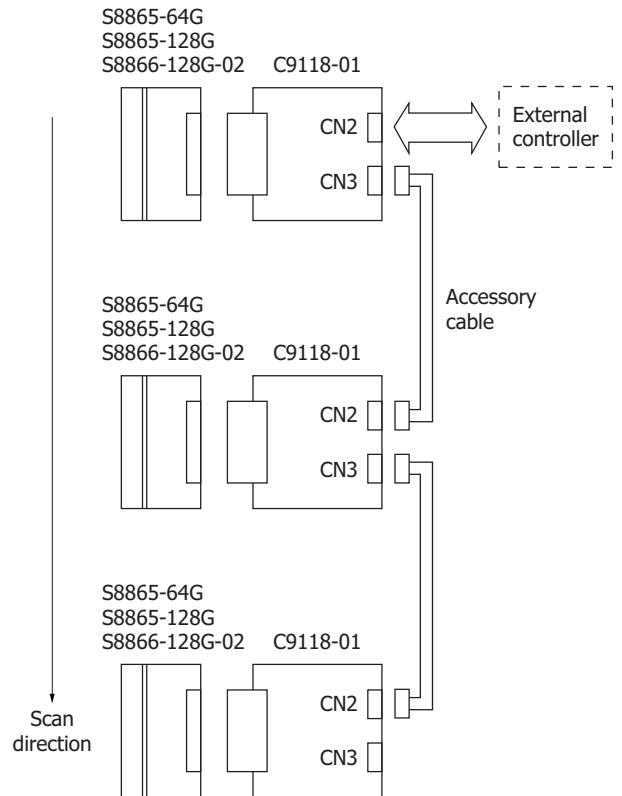
Simultaneous integration/output
(effective for high-speed processing)



KACCC0431EC

Cascade readout example (C9118-01)

Simultaneous integration/serial output
(Simplifies external processing circuit)



KACCC0432EC

Information described in this material is current as of January, 2012.

Product specifications are subject to change without prior notice due to improvements or other reasons. Before assembly into final products, please contact us for the delivery specification sheet to check the latest information.

Type numbers of products listed in the delivery specification sheets or supplied as samples may have a suffix "(X)" which means preliminary specifications or a suffix "(Z)" which means developmental specifications.

The product warranty is valid for one year after delivery and is limited to product repair or replacement for defects discovered and reported to us within that one year period. However, even if within the warranty period we accept absolutely no liability for any loss caused by natural disasters or improper product use.

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